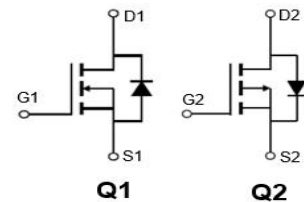
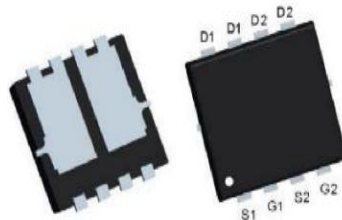


30V/-30V N and P-Channel Enhancement Mode MOSFET

Features

- Q1: $V_{DS}=30V; I_D=40A$
- Q1: $R_{DS(ON)}=10m\Omega$ (TYP.) $V_{GS}=10V, I_D=$
- Q2: $V_{DS}=-30V; I_D=-25A$
- Q2: $R_{DS(ON)}=-25m\Omega$ (TYP.) $V_{GS}=-10V, I_D$
- Reliable and Rugged
- Avalanche Rated
- Low On-Resistance
- High Current Capability

PDFN5060



Ordering Information

Device	package	Device Marking	Package Qty.
AGM310MA	PDFN5060	AGM310MA	5000/PCS

Absolute Maximum Ratings (T_A=25°C, unless otherwise noted)

Parameter	Symbol	Value(Q1)	Value(Q2)	Unit
Drain-Source Voltage ($V_{GS}=0V$)	V_{DS}	30	-30	V
Gate-Source Voltage ($V_{GS}=0V$, static)	V_{GS}	± 20	± 20	V
Continuous Drain Current ($T_C=25^\circ C$)	I_D	40	-25	A
Continuous Drain Current ($T_C=100^\circ C$)		30	-20	A
Single Pulsed Avalanche Energy	E_{AS}	-	-	mJ
Maximum Power Dissipation ($T_C=25^\circ C$)	P_D	33.5	28	W
Operating, Storage Temperature Range	T_J, T_{STG}	-55~150	-55~150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	N-CH	P-CH	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	3.6	5.4	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62	62	$^\circ C/W$

Q1:Electrical Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	30	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=40V, V_{GS}=0V$	-	-	1	μA
Gate -Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2	-	2.5	V
Drain-Source On-stage Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=1A$	-	7.5	10	m Ω
		$V_{GS}=4.5V, I_D=1A$	-	11	18	

Dynamic Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$V_{DS}=20V$	-	930	-	pF
Output capacitance	C_{oss}	$V_{GS}=0V$	-	118	-	
Reverse transfer capacitance	C_{rss}	$f=1MHz$	-	100	-	
Gate Resistance	R_g	$f=1MHz$	-	3.0	-	Ω
Total Gate Charge	Q_g	$V_{DS}=20V$	-	9	-	nC
Gate Source Charge	Q_{gs}	$V_{GS}=10V$	-	4	-	
Gate Drain Charge	Q_{gd}	$I_D=6A$	-	3.3	-	
Turn-on delay Time	$t_{d(on)}$	$V_{GS}=10V$	-	3	-	ns
Rise time	t_r	$V_{DS}=20V$	-	6	-	
Turn-off delay Time	$t_{d(off)}$	$R_L=3.2\Omega$	-	28	-	
Fall time	t_f	$R_G=3\Omega$	-	3	-	

Reverse Diode Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Body Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=1A$	-	-	1.0	V
Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_{SD}=6A$	-	8.5	-	ns
Reverse Recovery Charge	Q_{rr}	$dI/dt=500A/\mu s$	-	2.2	-	nC

Q1:Electrical Characteristics Diagrames

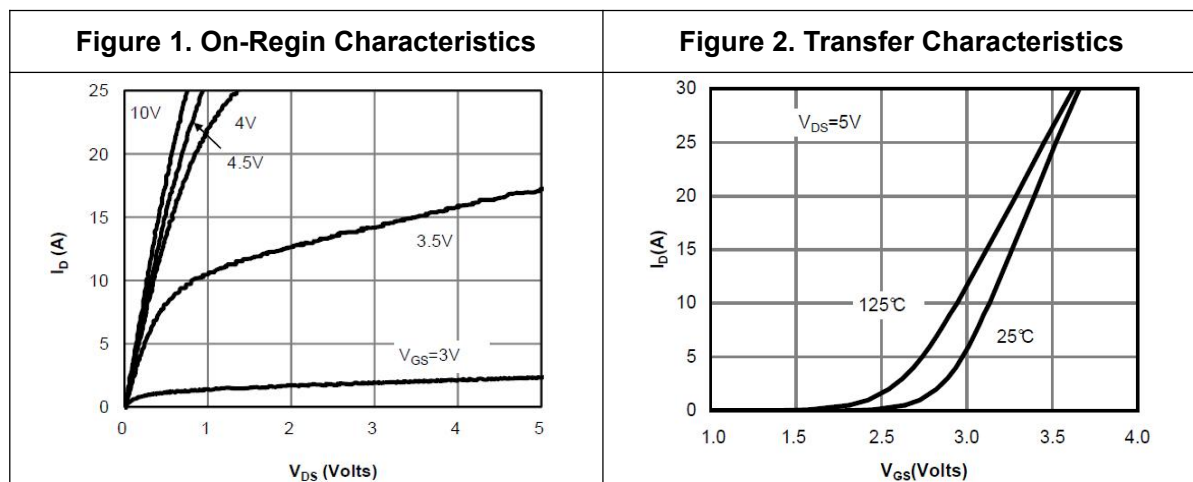


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

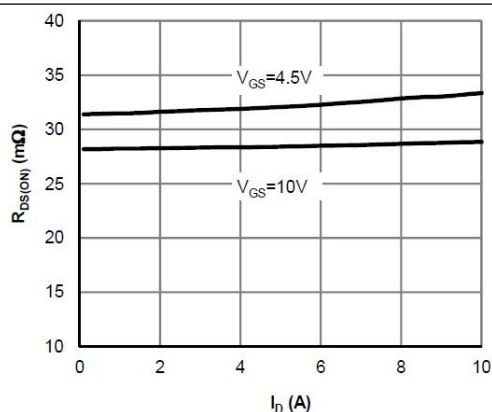


Figure 4. On-Resistance vs. Junction Temperature

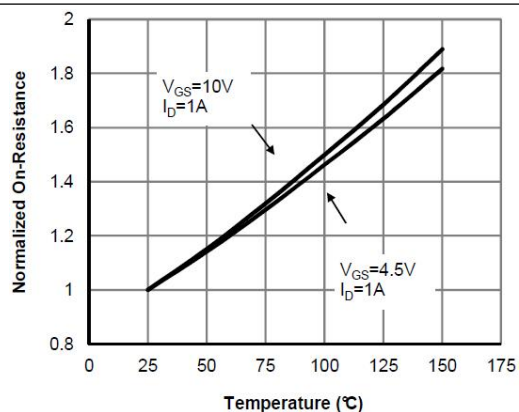


Figure 5. On-Resistance vs. Gate-Source Voltage

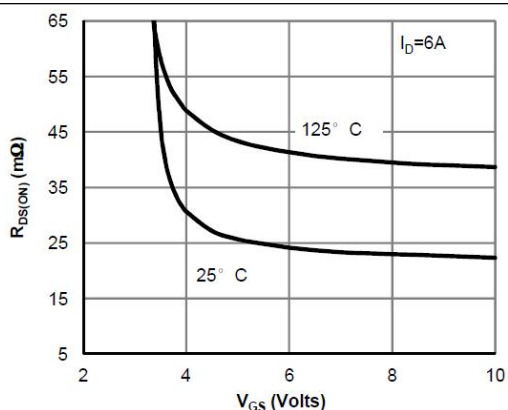


Figure 6. Body-Diode Characteristics

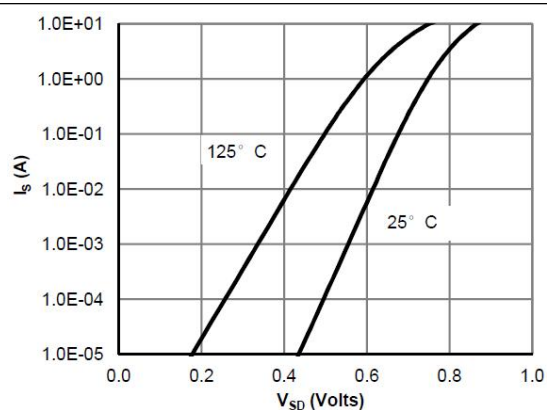


Figure 7. Gate-Charge Characteristics

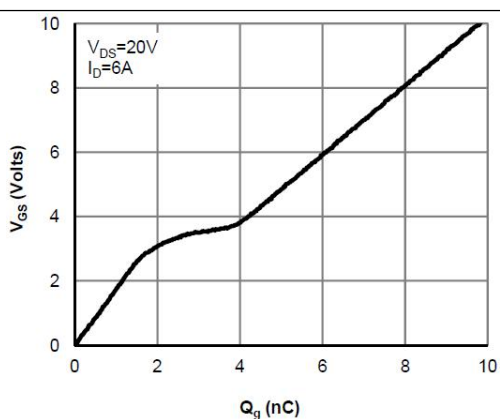
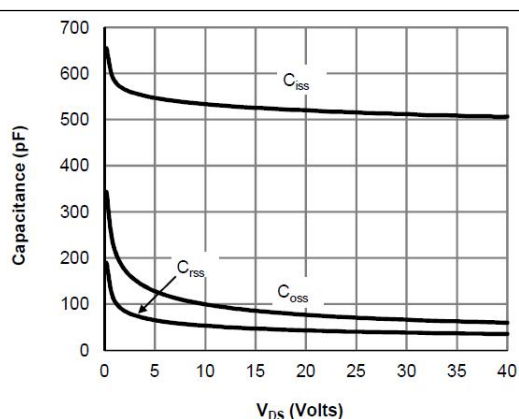


Figure 8. Capacitance Characteristics



Q2:Electrical Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=-250\mu A$	-30	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=-40V, V_{GS}=0V$	-	-	-1	μA
Gate -Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1	-1.5	-2.5	V
Drain-Source On-stage Resistance	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-1A$	-	19	25	m Ω
		$V_{GS}=-4.5V, I_D=-1A$	-	27	35	

Dynamic Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$V_{DS}=-20V$	-	1050	-	pF
Output capacitance	C_{oss}	$V_{GS}=0V$	-	140	-	
Reverse transfer capacitance	C_{rss}	$f=1MHz$	-	130	-	
Gate Resistance	R_g	$f=1MHz$	-	-	-	Ω
Total Gate Charge	Q_g	$V_{DS}=-20V$	-	50	-	nC
Gate Source Charge	Q_{gs}	$V_{GS}=-10V$	-	9.5	-	
Gate Drain Charge	Q_{gd}	$I_D=-5A$	-	8.1	-	
Turn-on delay Time	$t_{d(on)}$	$V_{GS}=-10V$	-	12	-	ns
Rise time	t_r	$V_{DS}=-20V$	-	14	-	
Turn-off delay Time	$t_{d(off)}$	$R_L=4\Omega$	-	195	-	
Fall time	t_f	$R_G=3\Omega$	-	95	-	

Reverse Diode Characteristics

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Body Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=-1A$	-	-	-1.2	V
Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_{SD}=-5A$	-	23	-	ns
Reverse Recovery Charge	Q_{rr}	$di/dt=500A/\mu s$	-	14	-	nC

Q2:Electrical Characteristics Diagrames

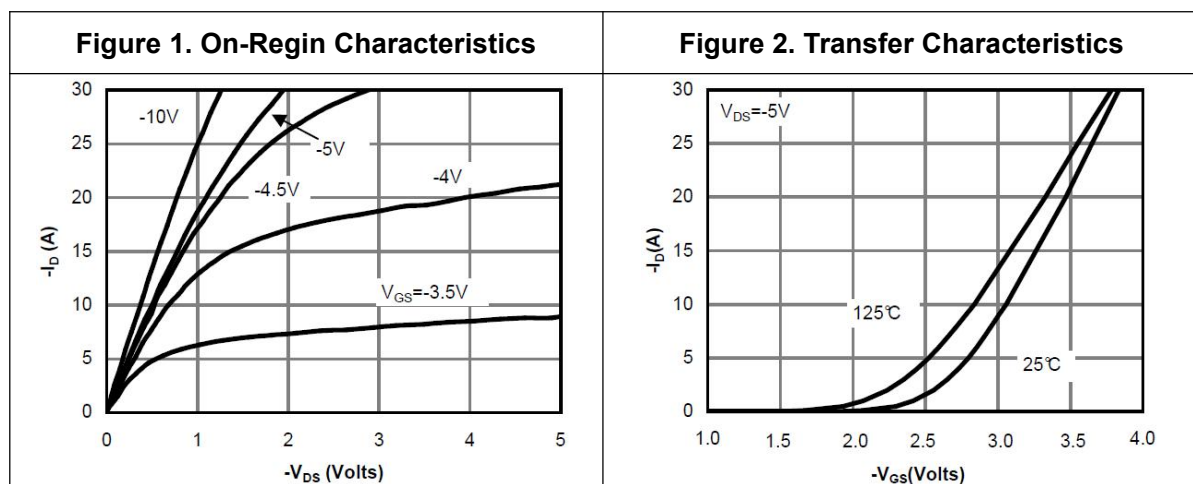


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

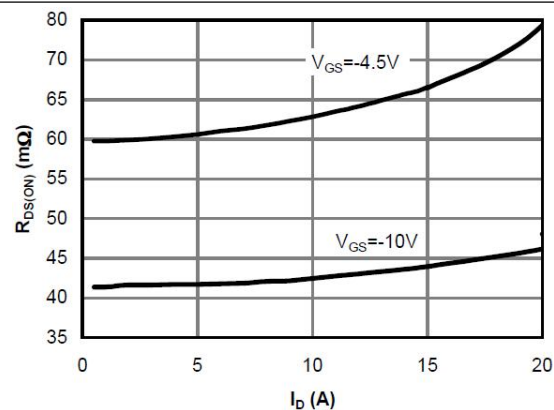


Figure 4. On-Resistance vs. Junction Temperature

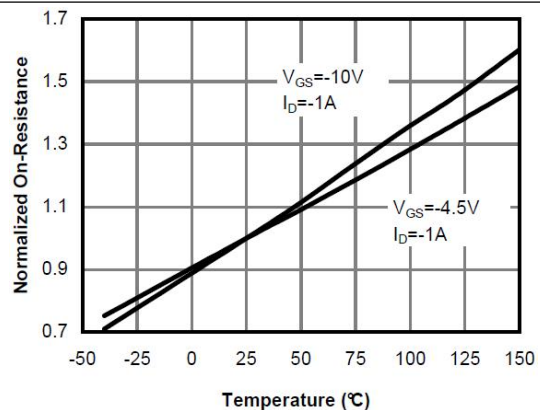


Figure 5. On-Resistance vs. Gate-Source Voltage

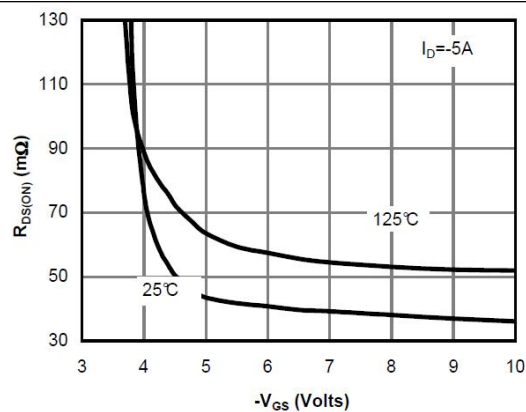


Figure 6. Body-Diode Characteristics

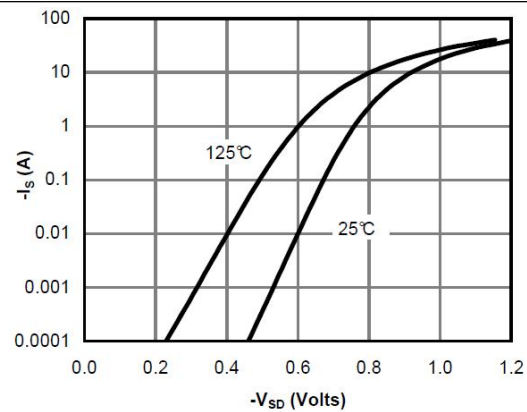


Figure 7. Gate-Charge Characteristics

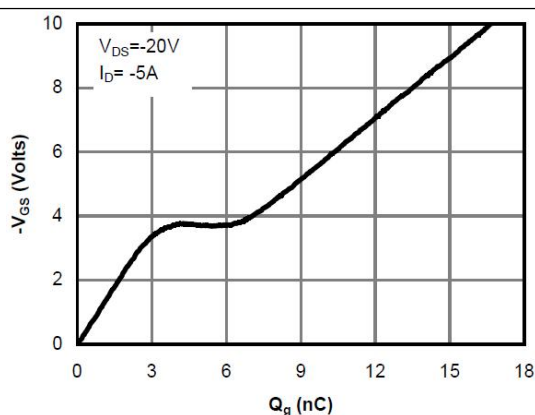
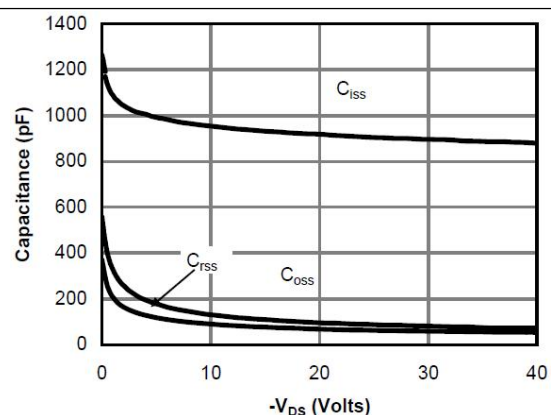


Figure 8. Capacitance Characteristics



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